

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. 01-471/1D / LSI1P172D1	Application No.: Filed Herewith 10/772 133
	Applicant: CATABAY et al. Filing Date 2/3/04 Herewith	Group Unassigned

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
TN	A	5,925,415	07/20/99	Fry et al.	427	304	03/09/98
	B	6,010,962	01/04/00	Liu et al.	438	687	02/12/99
	C	6,015,749	01/18/00	Liu et al.	438	628	05/04/98
	D	6,022,808	02/08/00	Nogami et al.	438	694	03/16/98
	E	6,037,258	03/14/00	Liu et al.	438	687	05/07/99
	F	6,042,889	03/28/00	Ballard et al.	427	305	02/28/94
	G	6,066,892	05/23/00	Ding et al.	257	751	05/14/98
	H	6,162,727	12/19/00	Schonauer et al.	438	687	11/25/98
	I	6,235,406	05/22/01	Uzoh	428	620	07/13/00

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
TN	O	Wolfe, et al., Silicon Processing for the VLSI Era, Vol. 1 – Process Technology, 2 nd Ed., Lattice Press: Sunset Beach, CA, 2000, pp. 791-795.
TN	P	U.S. Patent Application No. 10/035,705, "Electroless Deposition of Copper to Form Copper Interconnect Structures", filed 10/18/01.
	Q	
Examiner <i>T. Nguyen</i>		Date Considered <i>4/6/06</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. 01-471/1D / LSI1P172D1	Application No.: Filed Herewith 10/772133
	Applicant: CATABAY et al. Filing Date Herewith 2/3/04	Group Unassigned

U.S. Patent Documents

US Patent Documents							
Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
TN	AA	6,255,192B1	07/03/01	Dornisch	438	430	09/09/98
	BB	6,268,291B1	07/31/01	Andricacos et al.	438	694	12/03/98
	CC	6,287,968B1	09/11/01	Yu et al.	438	675	01/04/99
	DD	6,297,158B1	10/02/01	Liu et al.	438	687	05/31/00
	EE	6,328,871B1	12/11/01	Ding et al.	205	183	08/16/99
	FF	6,368,967B1	04/09/02	Besser	438	687	05/04/00
	GG	6,376,370B1	04/23/02	Farrar	438	678	01/18/00
	HH	6,391,777B1	05/21/02	Chen et al.	438	687	05/02/01
	II	6,429,121B1	08/06/02	Hopper et al.	438	686	02/07/01

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	JJ							
	KK							
	LL							
	MM							
	NN							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	OO	
	PP	
	QQ	
Examiner	T. NGUYEN	
	Date Considered	4/6/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. 01-471/1D / LSI1P172D1	Application No.: Filed Herewith 10/772133
	Applicant: CATABAY et al. Filing Date Herewith 2/3/04	Group Unassigned

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
TN	AAA	6,440,849B1	08/27/02	Merchant et al.	438	658	10/18/99
	BBB	6,445,070B1	09/03/02	Wang et al.	257	751	01/29/01
	CCC	6,461,675B2	10/08/02	Paranjpe et al.	427	250	07/10/98
V	DDD	6,465,376B2	10/15/02	Uzoh et al.	438	927	08/18/99
	EEE						
	FFF						
	GGG						
	HHH						
	III						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	JJJ							
	KKK							
	LLL							
	MMM							
	NNN							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	OOO	
	PPP	
	QQQ	
Examiner	T. NGUYEN	
	Date Considered	4/6/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.